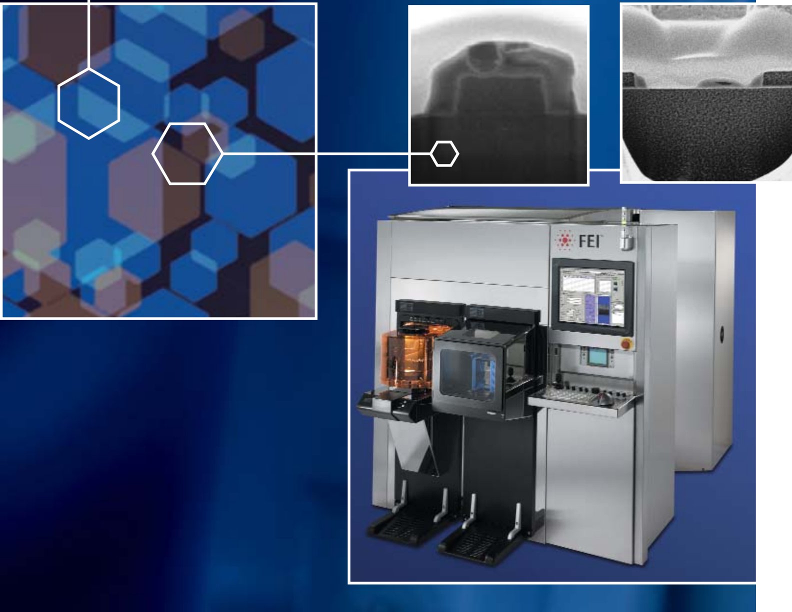
PRODUCT DATA

FEI COMPANY™



Defect Navigation Option for IC3D™ Software on CLM-3D™ DualBeam™ Workstations

The CLM-3D™ is an in-line metrology tool specifically designed to meet the challenging requirements of the semiconductor fab. Automated features and a familiar user interface combine to increase operator efficiency and product throughput. Flexible automation allows for multiple user applications.

• Provides Defect Navigation
  - Simple navigation of KLARF files
  - Filtering and sorting site list
  - Support analysis during production ramp

• Works with Yield Management Systems
  - Transfer defect files and images
  - Includes option to automatically export files at end of recipe

• Allows Defect Classification
  - Manually classify defects

• Supports a Variety of Images
  - Optical
  - SEM
  - FIB

Convenient Data Availability

In-fab automated structural metrology is now complemented with the Defect Navigation option for IC3D™ Software. This option offers the following additional functionality to your system:

- Import defect files
- Filter and sorting defect information
- Classify defects manually
- Export defect files with classification data and images

Yield Management

You can easily transfer defect files and images from Defect Navigation to your factory's yield management system. Defect Navigation supports single directory output for fast access by the yield management system's file sniffer. For yield management systems on UNIX operation systems, Defect Navigator exports files in a universal format and directory structure for ease of file access and use.

Defect Classification

You can manually classify defects using optical, SEM or FIB images. At the end of a recipe, Defect Navigation allows the automatic export the defect classification data and images.

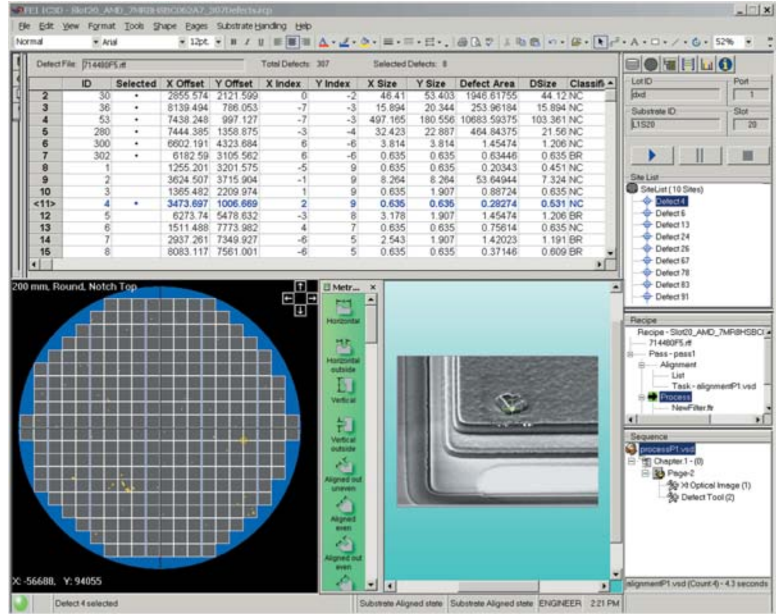
User Interface

The main screen in Defect Navigation provides an intuitive interface to many of the software's features. In the upper left is the defect spreadsheet, displaying data from the loaded defect file. In the right column is the defect site list, displaying the list of defect numbers selected from the defect spreadsheet. File names for the defect file and the defect filter file with the network path are also displayed in the right column. The lower left area of the screen displays the wafer map, which is linked to the spreadsheet, with wafer statistics, defect data and navigational indication. The defect tool gizmo, which is used for the manual defect classification, is in the lower center portion of the screen.

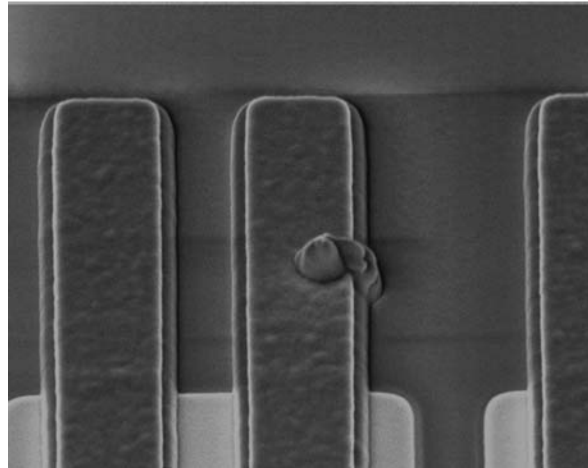
Defect Navigation provides an inline option for basic defect navigation on your CLM-3D system in the development phase of high-end fabs.

FEI Support/Service

Customer service and support are a key part of FEI's value. Our customer support organization of more than 40 offices around the world services our worldwide installed base. Services include system installation, on-site repair, software upgrades, training, telephone support and post-sales applications.



Intuitive graphical interface for ease of use and high productivity.



Navigate to defects with IC3D Software on the CLM-3D system.

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TOOLS FOR NANOTECH

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